

Screening Current-Induced Magnetic Field in a Non-Insulated GdBCO HTS coil for the 24 T All-Superconducting Magnet

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Outline

- Motivation and Background
- Simulation Model and Method
- Experiment Setup
- Results
- Conclusion

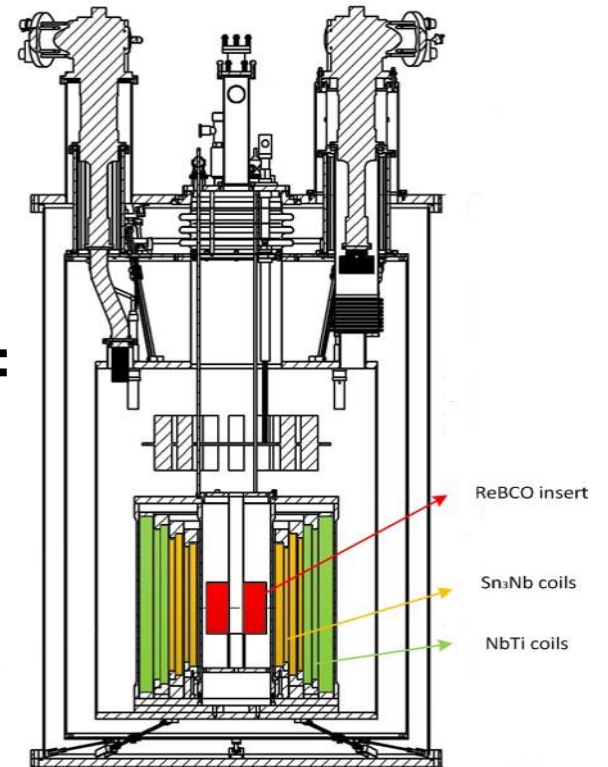
Motivation and Background



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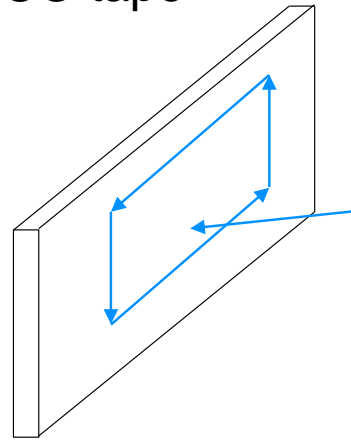
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Motivation and Background



REBCO tape



External Magnetic Field:

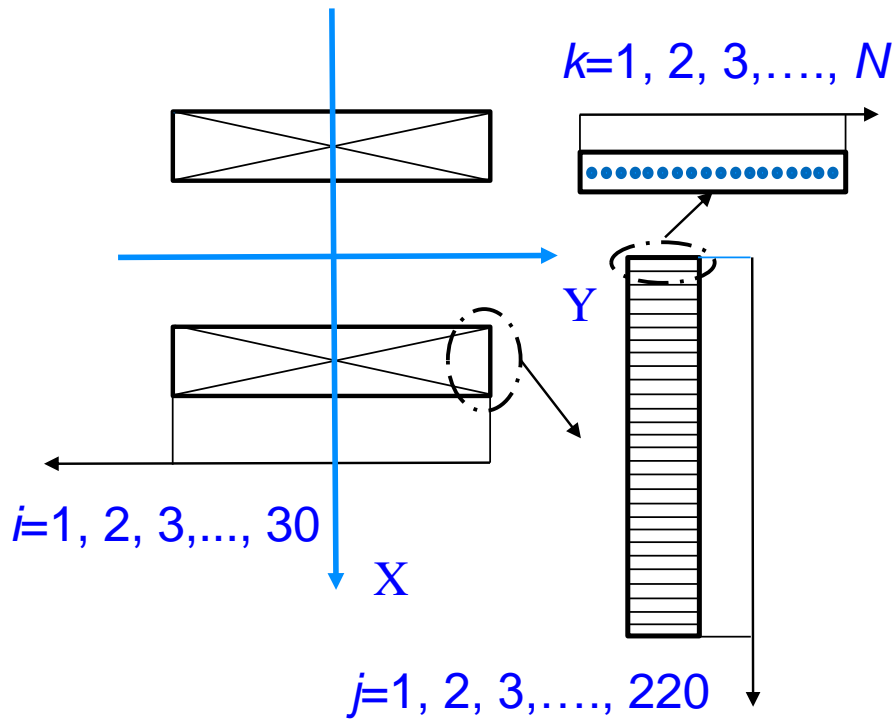
- LTS Outsert
- Other turns in the HTS Insert

Screening Current Deterioration:

- **Field Reduction (central)**
- Field Homogeneity
- Field Repeatability : charge and discharge
- Temporal Stability : flux creep motion

REBCO HTS insert

Simulation Model and Method



Specifications of HTS insert

Parameter	Value
Inner Diameter	32 mm
Outer Diameter	104 mm
Coil Height	150 mm
Turns per DP	220*2
Number of DP	15
B_0 per Ampere	0.055 T
Max Br	3.72

Simulation Model of HTS insert

Simulation Model and Method

Only charging I_t in the HTS (I_t and $B_r(i,j)$)

$$J(i, j, k) = \frac{J_c(i, j)}{\pi} [H - L + \pi] \quad |y_0(i, j, k) - p| < a$$

$$J(i, j, k) = J_c(i, j) \quad a < |y_0(i, j, k) - p| < w_0$$

$$H = \arcsin\left(\frac{(y(i, j, k) - p) \cdot (w_0 - p) - a^2}{a \cdot (w_0 - y(i, j, k))}\right)$$

$$L = \arcsin\left(\frac{(y(i, j, k) - p) \cdot (w_0 + p) + a^2}{a \cdot (w_0 + y(i, j, k))}\right)$$

$$J(i, j, k) = \frac{J_c(i, j)}{\pi} [H + L] \quad |y_0(i, j, k) - p| < a$$

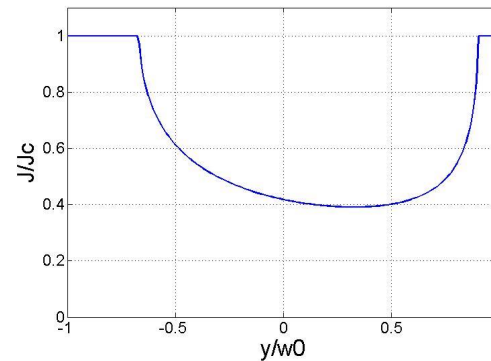
$$J(i, j, k) = J_c(i, j) \quad -w_0 < y_0(i, j, k) < p - a$$

$$J(i, j, k) = -J_c(i, j) \quad p + a < y_0(i, j, k) < w_0$$

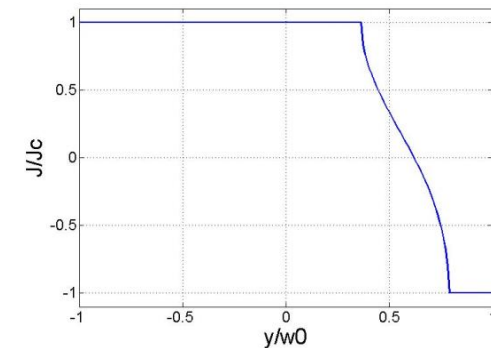
$$p = w_0 (I_t / I_c(i, j)) \tanh(B_r(i, j) / B_p(i, j))$$

$$a = (w_0 / \cosh(B_r(i, j) / B_p(i, j))) \sqrt{1 - (I_t / I_c(i, j))}$$

Criterion $m(i, j) = \frac{I_t}{I_c(i, j)} - \tanh\left(\frac{B_r(i, j)}{B_p(i, j)}\right)$



$m(i,j) > 0$



$m(i,j) < 0$



Simulation Model and Method

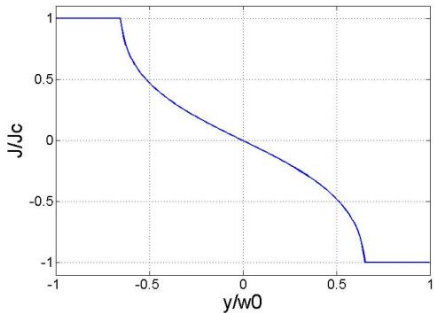
First, Charging the LTS Outsert ($B_1(i,j)$)

$$J_1(i, j, k) = \frac{-2J_{c(i,j)}}{\pi} \cdot \arctan\left(\frac{y(i, j, k)}{w_0} \sqrt{\frac{w_0^2 - a_1^2}{a_1^2 - y(i, j, k)^2}}\right) \quad -a < y(i, j, k) < a$$

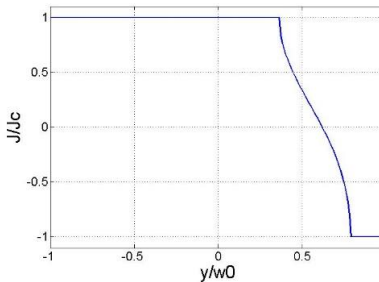
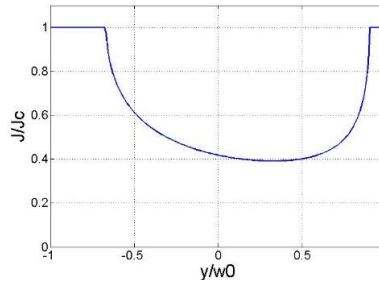
$$J_1(i, j, k) = -J_{c(i,j)} \quad a_1 < y(i, j, k) < w_0$$

$$J_1(i, j, k) = J_{c(i,j)} \quad -w_0 < y(i, j, k) < -a_1$$

$$a_1 = w_0 / \cosh(B_1(i, j) / B_p(i, j))$$



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Second, Charging the HTS Insert:

$$J = J_{LTS} + J_{HTS} ?$$

NO! The conductor is not from a virgin state



Simulation Model and Method

LTS First, HTS Second ($I_2(i,j)$ and $B_2(i,j)$, $m_2(i,j) > 0$)

$-a < y(k_1) < p_2 - a_2$ $p_2 - a_2 < y(k_2) < p_2 + a_2$, $p_2 + a_2 < y(k_3) < w_0$

$$J_2(k_1) = J_c(i) - J_1(k_1) \quad -a < y(k_1) < p_2 - a_2$$

$$J_2(k_3) = J_c(i) - J_1(k_3) \quad p_2 + a_2 < y(k_3) < w_0$$

$$J_2(k_2) = \int_A \frac{-J_2(k_1)}{\pi} \left[\arcsin\left(\frac{\alpha(\beta + \kappa) + 2Ma_2}{\gamma + \kappa}\right) - \arcsin\left(\frac{\alpha(\beta - \kappa) + 2Ma_2}{\gamma - \kappa}\right) \right] \\ + \int_C \frac{J_2(k_3)}{\pi} \left[\arcsin\left(\frac{\alpha(\beta_1 + \kappa_1) - 2Ma_2}{\gamma_1 + \kappa_1}\right) - \arcsin\left(\frac{\alpha(\beta_1 - \kappa_1) - 2Ma_2}{\gamma_1 - \kappa_1}\right) \right]$$

$$\alpha = 2M(y(k_2) - p_2)$$

$$\beta = 2M(y(k_1) - p_2) \quad \beta_1 = 2M(y(k_3) - p_2)$$

$$\kappa = w_0 + p_2 - a_2 \quad \kappa_1 = w_0 - p_2 - a_2$$

$$\gamma = 2M(y(k_1) + y(k_2)) \quad \gamma_1 = 2M(y(k_3) - y(k_2))$$

$$I_t = \frac{2w_0 d_0}{N} \int_{-w_0}^{w_0} J_2(k)$$

$$-B_2(i, j) = \frac{\mu_0 d_0}{2\pi} \int_{-w_0}^{w_0} \frac{J_2(k)}{y(k) - p_2}$$

p_2 and a_2

$$J_3(i, j, k) = J_1(i, j, k) + J_2(i, j, k)$$



Simulation Model and Method

Central Field Reduction

$$B_c = \sum B_c(i, j, k) = \sum_{\substack{i=1:1:30 \\ j=1:1:220}} \frac{\mu_0 J(i, j, k) w_0 d_0 x(i, j, k)^2}{N(x(i, j, k)^2 + y(i, j, k)^2)^{3/2}}$$

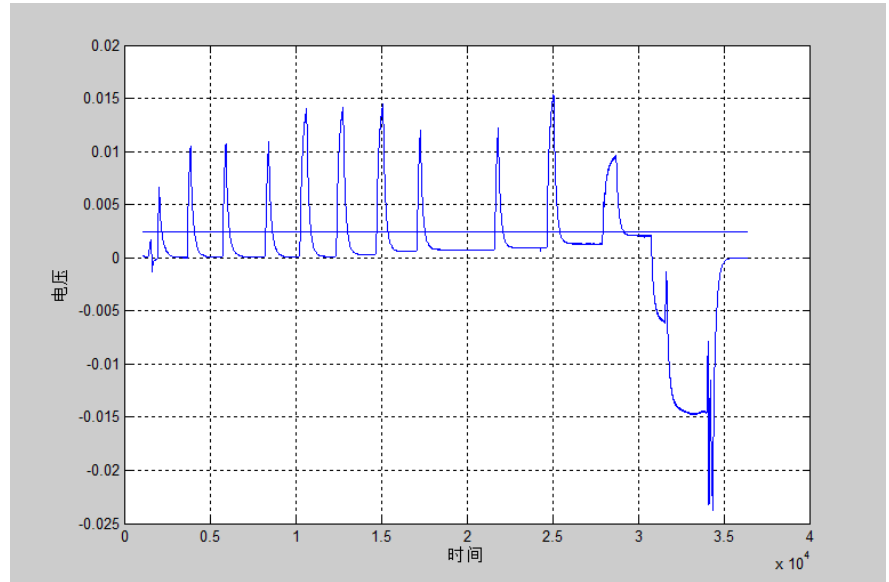
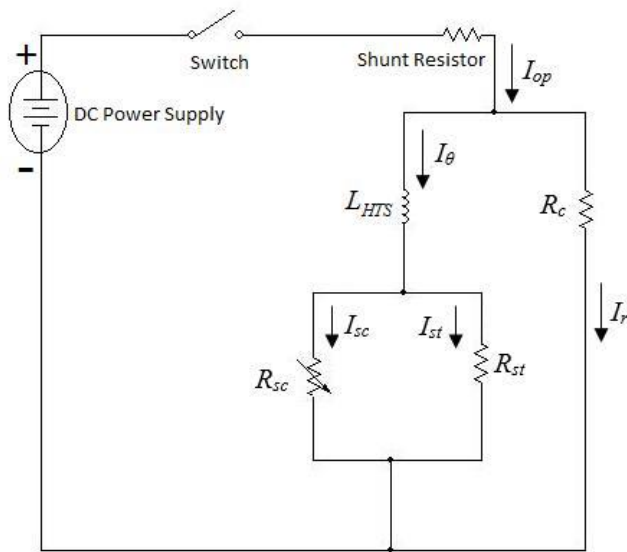
$$B_i = I_t * B_0$$

$$B_{fr} = B_c - B_i$$

B_0 - axial field per ampere at center 0.055 T/A

Experiment Setup

Equivalent Circuit Model



$$L_{HTS} \frac{dI_\theta}{dt} = I_r R_c$$

$$I_\theta + I_r = I_{op}$$

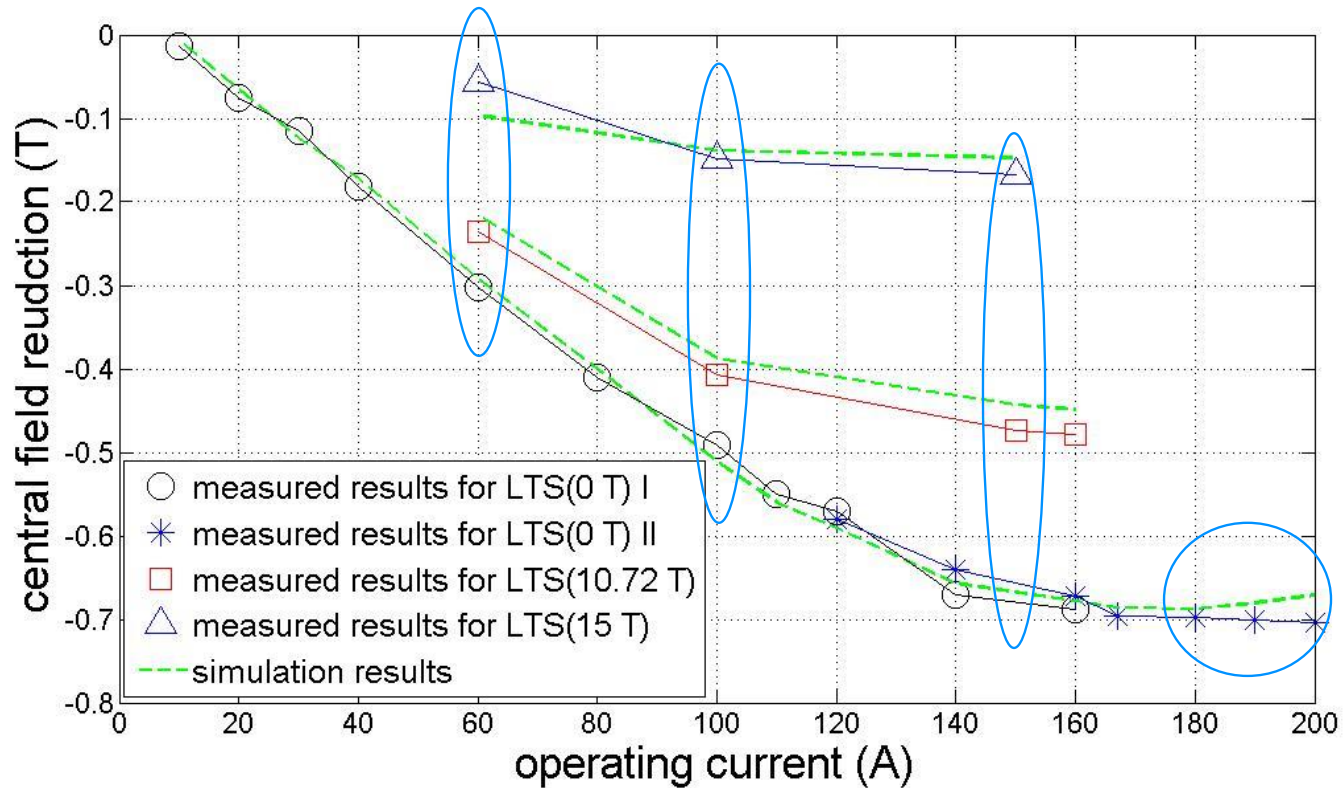
$$\tau = 69 \text{ s}$$

Experiment Setup

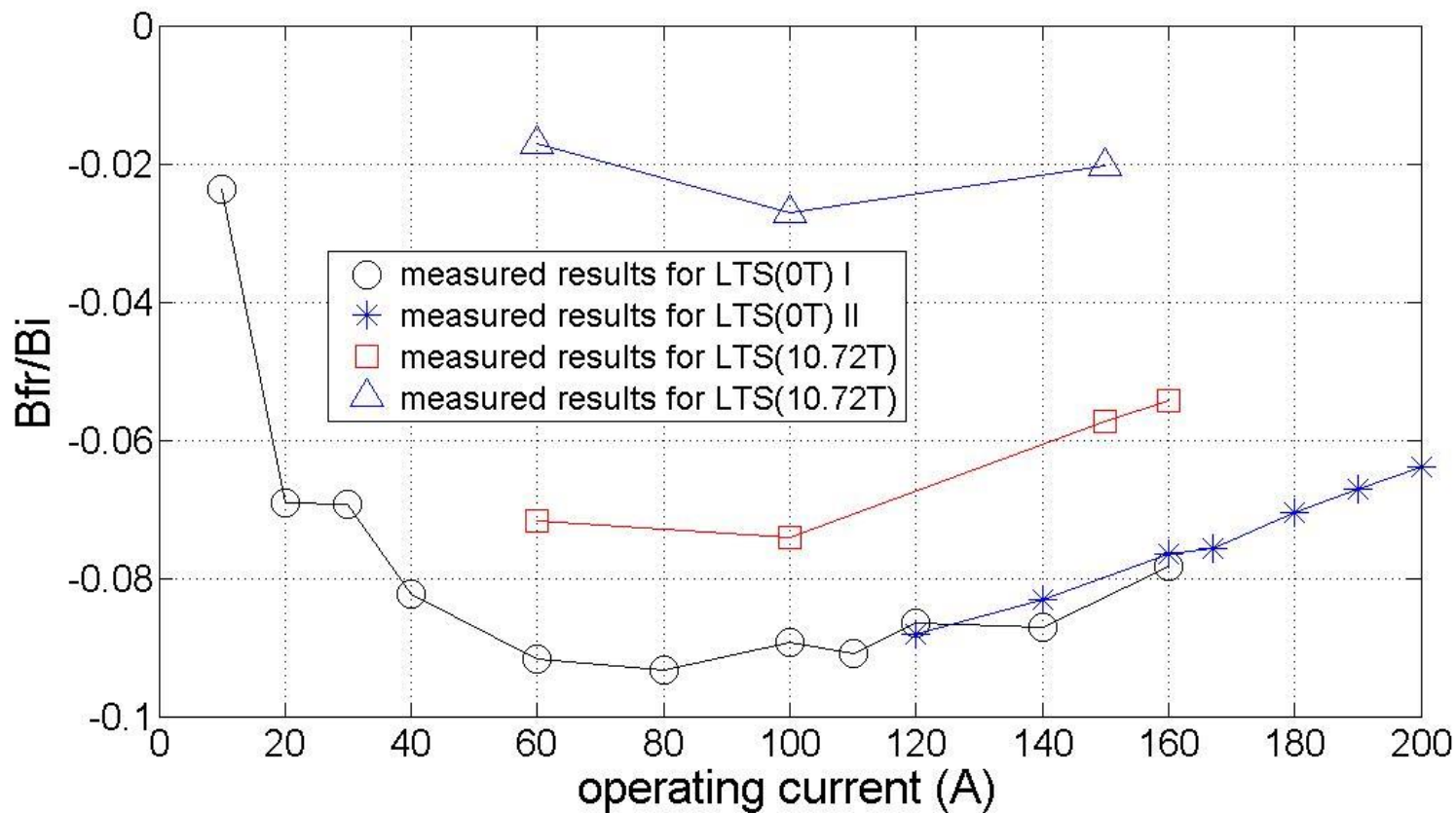
Charging Test

- Charging HTS insert only: series I (0 A - 160 A)
- Charging HTS insert only: series II (0 A - 200 A)
- Charging the LTS outsert with central field of 10.72 T, and then the HTS insert
- Charging the LTS outsert with central field of 15 T, and then the HTS insert

Results



Results



Conclusions

- B_{fr} is studied by the simulation results and experimental data, which show a good agreement.
- B_{fr} is not affected by the ramping rate of the operation current.
- The reduction of B_{fr} is as large as 75% when the central field of LTS outsert increases to 15 T.

Thank you

